

<b>Notice of References Cited</b>	Application/Control No. 10/774,590		Applicant(s)/Patent Under Reexamination NONAKA ET AL.	
	Examiner DAVID P. RASHID		Art Unit 2624	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,594,311	07-2003	Pearlstein, Larry	375/240.01
*	B	US-5,991,503	11-1999	Miyasaka et al.	386/111
*	C	US-2001/0033737	10-2001	Honjo, Masahiro	386/52
*	D	US-6,181,743	01-2001	Bailleul, Nicolas	375/240
*	E	US-2002/0059643	05-2002	Kitamura et al.	725/136
*	F	US-2002/0067768	06-2002	Hurst, Robert N.	375/240.03
*	G	US-6,415,055	07-2002	Kato, Motoki	382/236
*	H	US-2002/0114397	08-2002	TODO et al.	375/240.29
*	I	US-2002/0136310	09-2002	Saunders et al.	375/240.25
*	J	US-2002/0181595	12-2002	OBATA et al.	375/240.25
*	K	US-2002/0186769	12-2002	O'Brien, Royal	375/240.12
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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